

CMP COST ISSUES & IMPACT ON CONSUMABLES FOR MEMORY AND LOGIC

CMPUG @CNSE April 16, 2016

Mike Corbett Managing Partner mcorbett@linx-consulting.com



Agenda



- INTRODUCTION TO LINX CONSULTING
- SEMI INDUSRTY OUTLOOK
- COST TRENDS IN LEADING EDGE SEMICONDUCTOR DEVICES
- OUTLOOK FOR CMP/CONCLUSIONS



LINX BACKGROUND

See Beyond the Horizon

Linx Consulting



- 1. We help our clients to succeed by creating knowledge and developing unique insights at the intersection of electronic thin film processes and the chemicals industry
- 2. The knowledge is based on a core understanding of the semiconductor device technology; manufacturing processes and roadmaps; and the structural industry dynamics
- *3. This knowledge is leveraged to create advanced models, simulations and real-world forecasts*
- 4. Our perspectives are by direct research and leveraging our extensive experience throughout the global industry value chain, including:
 - Experience in global electronics and advanced materials and thin film processing industries
 - Experience in the global chemicals industry
 - Experience at Device Producers
 - Experience at OEMs



Linx Consulting Service Portfolio

 Multi-Client Reports IC Materials CMP Deposition Patterning Cleaning Gases III-Vs, TSV, WLP, Solar 	 Proprietary Projects Market Planning M & A Growth and Diversification Supply Chain Optimization Technology Commercialization Strategic Planning Voice of the Customer 				
 Econometric Semiconductor Forecast Financial planning Sales and Operational planning Forecasting Hilltop Economics LLC 	 Cost Modeling Client demand modeling Product development Bill of Materials quantification IC Knowledge, LLC 				
 Semi LCD PV 	– Nano Technology – LED/ Compound Semi				



Industry Analysis Reports Offered

CMP Focused:

- 1. CMP Technologies and Markets to the Sub-10nm Node (6th edition)
- 2. Specialty Abrasives in CMP (4th edition)
- 3. CMP in TSV (2nd edition)
- 4. Wafer Polishing Technologies and Markets
- 5. Advanced Thin Films for FEOL and BEOL Applications (5th Edition)
- 6. Advanced Cleaning and Surface Preparation: Technologies and Markets (5th Edition)
- 7. Advanced Patterning Forecasting (Semi-Annual)
- 8. Chemicals and Materials for TSV Applications
- 9. Electronic Specialty Gases
- 10. Global Market for MO Precursors
- 11. The Econometric Semiconductor Forecasting Service
- 12. Strategic Cost Model



SEMI INDUSTRY OUTLOOK

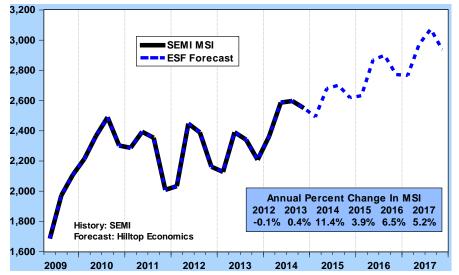
See Beyond the Horizon

www.linx-consulting.com

7



Econometric Semiconductor Forecast – Materials Demand Track Silicon



March 2015 Update	2014Q4	2015Q1F	2015Q2F	2015Q3F	2015Q4F
MSI	2550	2491	2679	2701	2619
%Change	-1.8%	-2.3%	7.6%	0.8%	-3.0%
%Change vs prior	15.5%	5.4%	3.6%	4.0%	2.7%
year					

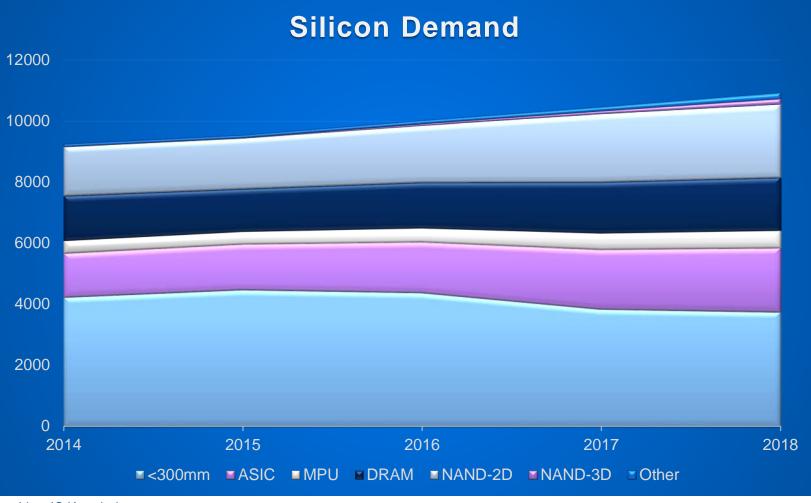
The mean absolute error is an exceptionally low 3.5%, an indication that the model and forecasting process has effectively captured semiconductor MSI's relationship to the macro economy.

Source: Hilltop Economics LLC

See Beyond the Horizon



Device Segmentation

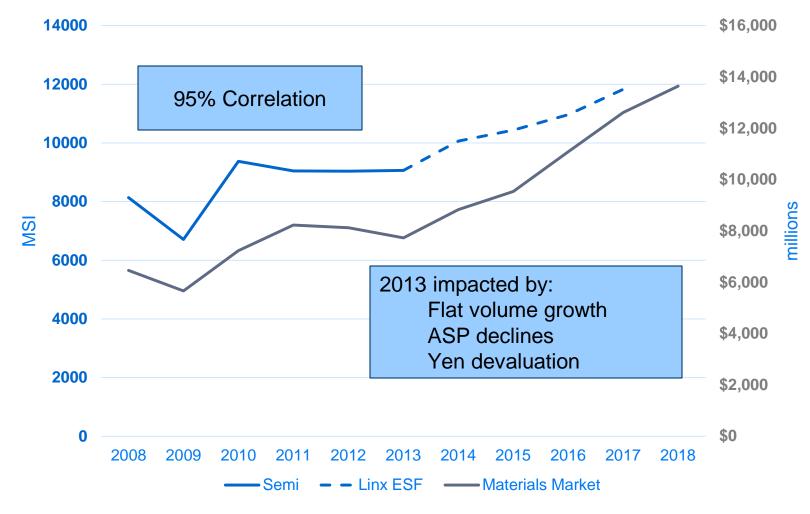


Linx, IC Knowledge

See Beyond the Horizon

Electronic Materials are Correlated to Silicon Demand

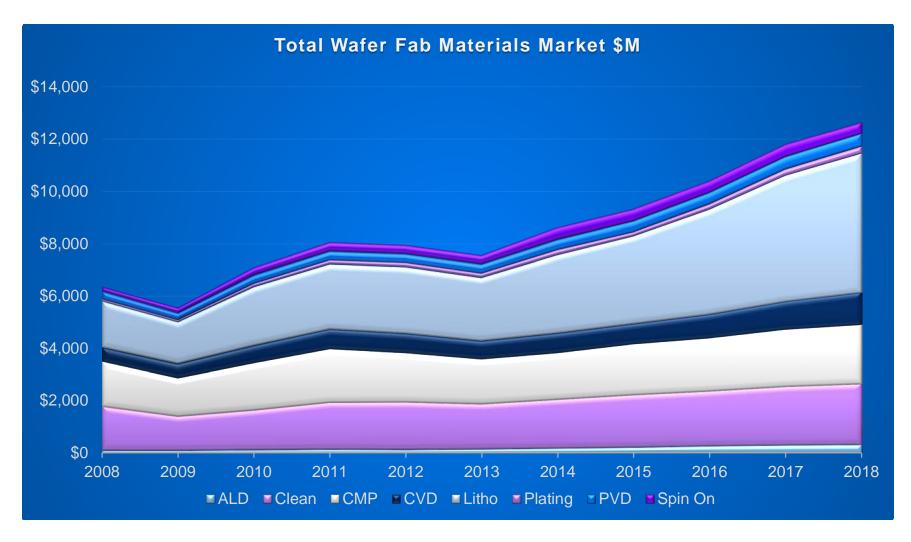




See Beyond the Horizon



Correlation of Materials to MSI



See Beyond the Horizon



COST ESTIMATES FOR CMP PROCESSING

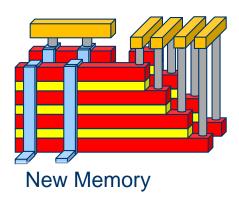
See Beyond the Horizon

www.linx-consulting.com

12

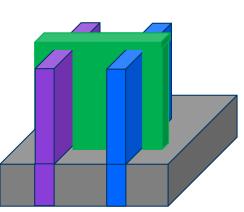
The Drivers of Change and Challenges for Manufacturing Technology



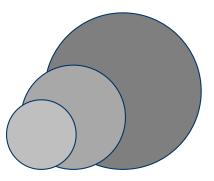


V	U	v	v	v	U	U	v	v	v	v	
U	U	v	v	v	U	v	v	v	v	v	

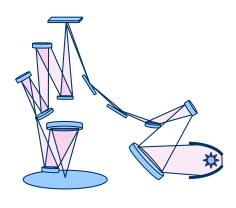
3D Packaging



Gate Architecture



450mm

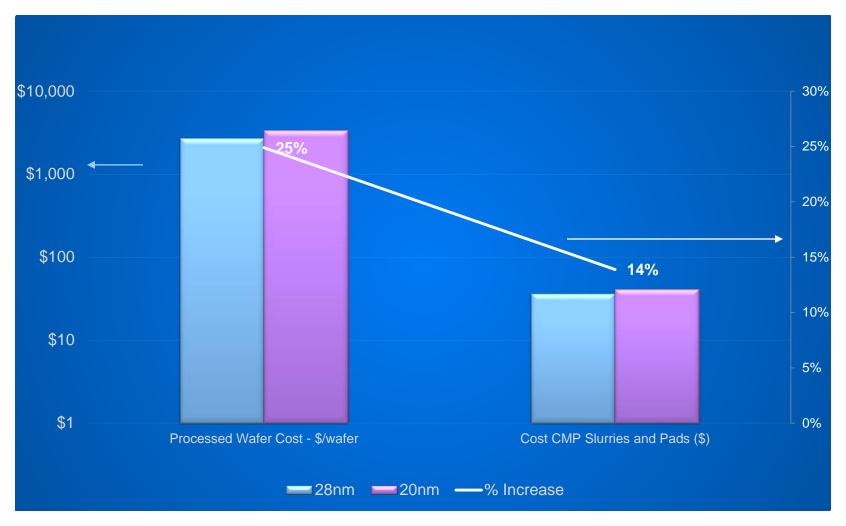


EUV

See Beyond the Horizon



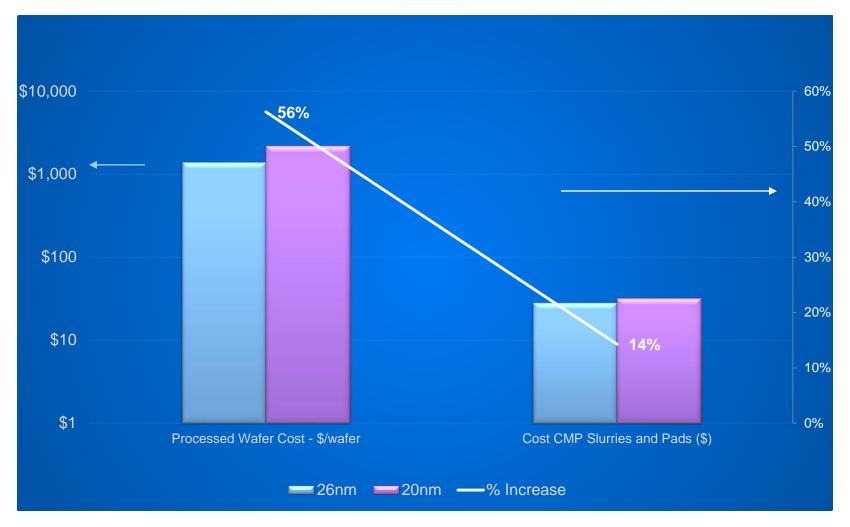
ASIC – Processed Wafer Costs



Source: strategic Cost Model, ICKnowledge and Linx Consulting See Beyond the Horizon



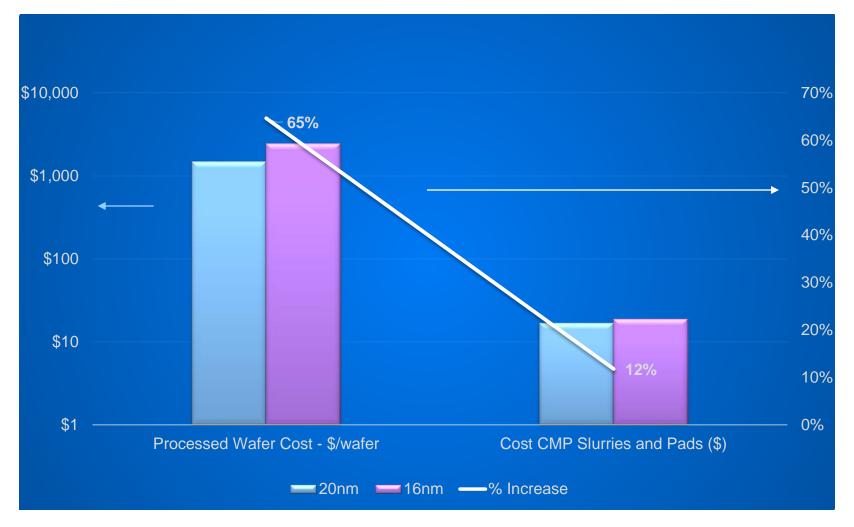
DRAM – Processed Wafer Costs



Source: strategic Cost Model, ICKnowledge and Linx Consulting See Beyond the Horizon



2D NAND – Processed Wafer Costs



Source: strategic Total OboOehdOldes OlephgeeiantionLinnaOutes altice; labor, facilities and consumables See Beyond the Horizon



CMP OUTLOOK

See Beyond the Horizon

www.linx-consulting.com

17

300mm Wafer Growth



See Beyond the Horizon



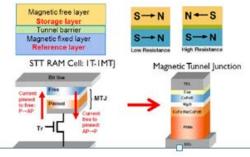
Memory Growth Drivers

Memory

BEOL Layers, W integration; Selective Oxides, Novel electrodes

Copper and Barrier CMP; W CMP, Ceria-based, Ru

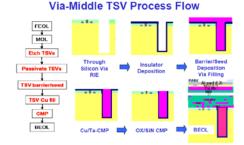
- Ru electrodes may be used with novel dielectrics for DRAM
- DRAM scaling comes to an end within ~ 5 years. TSV technology can be used to continue to scale density. HMC, etc.
- 2D and 3D NAND will be integrated simultaneously. @D structures will require higher planarity and 3D will open up new W polishes as well as oxide steps
- MRAM provides non-volatile storage, high read write speeds, lower energy dissipation and high write endurance

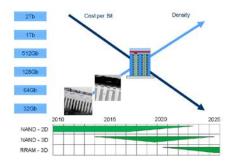




See Beyond the Horizon

Patrim Deposition Patrim of Bottom Excitode of Bottom Excitode extract Etching of Sacrificial layer Ru CMP Remove of Sacrificial layer



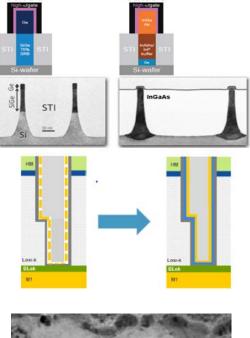




Logic Growth Drivers

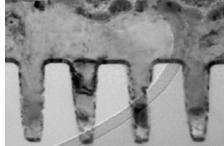


- IMEC has demonstrated the integration of highmobility channel InGaAs n-channel and Ge p-channel metal–oxide–semiconductor field-effect transistors
- CVD Co improves Cu wetting and extends Cu gap fill.
 CVD Co is thin, continuous, conformal layer that repairs any discontinuities for barrier/seed
- A cross-section TEM of a 50-nm trench structure coated with a ~5nm Ru:TaN liner followed by ECD copper. The filling characteristics are equivalent to seeded copper, and direct plated films possess generally larger grain size characteristics



NMOS

PMOS



Sources: Applied Materials, IMEC and Albany NanoTech

Conclusions



- Strong industry growth outlook over the next several years
- CMP Consumables are not major fab cost driver
- For 22nm and 14nm, the industry needs to have extremely tight control on the slurries and pad quality to control defects
- In advanced slurries, morphology of the slurry particles will be critical No agglomerations and angular particles
- Trend to low abrasives 0.5% or lower solids content as the slurry formulation trend is to greater chemo effect than mechanical effect
- Selectivity requirements will prove challenging to slurries as selectivity is increased and pads are tuned as a key point of the overall process control
- Defectivity control will be key for pads in terms of reducing scratching, dishing and erosion
- New applications in both memory and logic will continue to drive the opportunities for CMP going forward